Abstracts

A novel nonlinear statistical modeling technique for microwave devices

J.F. Swidzinski and K. Chang. "A novel nonlinear statistical modeling technique for microwave devices." 2000 MTT-S International Microwave Symposium Digest 00.2 (2000 Vol. II [MWSYM]): 887-890.

A novel nonlinear methodology for representing statistical variations of FET Equivalent Circuit Parameters (ECPs) and a new approach to yield estimation are presented. Proposed statistical nonlinear characterization is based on combination of applied multivariate methods with heuristic techniques, while proposed yield estimation method is based on Latin Hypercube Sampling (LHS). Practical examples validate the accuracy and efficiency of the methods.

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